

Notice of References Cited	Application/Control No. 10/803,352		Applicant(s)/Patent Under Reexamination FERNANDEZ ET AL.	
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*	B	US-5,814,821	09-1998	Reusch et al.	250/492.3
*	C	US-4,639,638	01-1987	Purcell et al.	313/534
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*	U	D.H. Dowell, "433 MHz High Duty Photocathode RF Gun Experiments", PERL Workshop, Jan. 22-23, 2001			
*	V	JLAB Monthly Report IR Demo FEL Upgrad and Comissioning Project, June 1998			
*	W	Michelato et al., "Cs2Te Photocathode for the TTF Injector II"			
*	X	IBM Technical Bulletin, October 1989, "Improving Brightness and Current of Phototelectron Lithography"			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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